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| Substitute | e for form | 1449A/PTO | | Complete if Known | | | | |
| | | | | Applica | etion Number | 10/51 | 6,583 | |
| INFC | RMA | TION DISCLOSU | IRE | | | Marc | arch 24, 2005 narles Eugene Stroud | |
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| UIA | | 01 | 13,4 | | | 2863 | | |
| | (Use as | many sheets as recessary) | 4 | Exami | ner Name | Dem | etrius R. Pretlow | |
| Sheet | Sheet 1 of 3 APR 13 7 | | 2 2007 8 | Attorney Docket Number | | 4687 | 872-308797 | |
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| Examiner | Examiner Cite Document Number ADEM ART Solo | | A STEPPICATION | n Date | Name of Patentee or Applicant of Cited Document | | Pages, Columns, Lines, Where Relevant | |
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| Initials* | Dale Api | | Applicant of Cited Document | Passages or Relevant Figures Appear | ₹ | |
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| | _ . | | 01 001105 | Application Number | 10/516,583 | |
| INFORMATION DISCLOSURE | | | | Filing Date | March 24, 2005 | |
| STATEMENT BY APPLICANT | | | PPLICANT | First Named Inventor | Charles Eugene Stroud | |
| | | | | Art Unit | 2863 | |
| | (Use as man | y sheets as | necessary) | Examiner Name | Demetrius R. Pretlow | |
| Sheet | 2 | of, | 3 | Attorney Docket Number | 46872-308797 | |

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| | | | CLOSURE | Filing Date | March 24, 2005 | |
| STATEMENT BY APPLICANT | | | | First Named Inventor | Charles Eugene Stroud | |
| | | | | Art Unit | 2863 | |
| | (Use as m | any sheets as | necessary) | Examiner Name | Demetrius R. Pretlow | |
| Sheet | 3 | of | 3 | Attorney Docket Number | 46872-308797 | |

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